

Locally Ion Implantation and Annealing Effects in Diamond

M.A. Pinault-Thaury, Mohamed Bouras, Raid Gourad, Karine Isoird, Fuccio Cristiano, Josiane Tasselli, Grégory Grosset, Yohan Spiegel, Rémi Gillet, François Jomard

▶ To cite this version:

M.A. Pinault-Thaury, Mohamed Bouras, Raid Gourad, Karine Isoird, Fuccio Cristiano, et al.. Locally Ion Implantation and Annealing Effects in Diamond. 3rd MOMENTOM INTERNATIONAL CONGRESS, Mar 2023, Gif-sur-yvette, France. 2023. hal-04271407

HAL Id: hal-04271407 https://hal.science/hal-04271407

Submitted on 6 Nov 2023

HAL is a multi-disciplinary open access archive for the deposit and dissemination of scientific research documents, whether they are published or not. The documents may come from teaching and research institutions in France or abroad, or from public or private research centers. L'archive ouverte pluridisciplinaire **HAL**, est destinée au dépôt et à la diffusion de documents scientifiques de niveau recherche, publiés ou non, émanant des établissements d'enseignement et de recherche français ou étrangers, des laboratoires publics ou privés.



Locally Ion Implantation and Annealing Effects in Diamond <u>M. Bouras</u>¹, R. Gourad², K. Isoird², F. Cristiano², J. Tasselli², G. Grosset³, Y. Spiegel³, R. Gillet¹, F. Jomard¹, M-A. Pinault-Thaury^{1*} ¹GEMaC-CNRS/UVSQ, Université Paris-Saclay, Versailles, France ²LAAS-CNRS, Université de Toulouse, CNRS, UPS, Toulouse, France ³Ion Beam Service, ZI Peynier Rousset, rue Gaston Imbert, F-13790, France

*marie-amandine.pinault-thaury@uvsq.fr

Diamond has demonstrated interesting properties for high power applications. However numerous technological obstacles make difficult the fabrication of power devices on diamond. Diamond doping in-situ gas phase is today the most efficient technique. In fact, the possibility to dope locally by ion implantation is indispensable for establishing a diamond manufacturing chain in particular to achieve the highest possible doping.

In 2014 successful incorporation of implanted phosphorus in (100) diamond donor sites show promising perspectives to process convinced implanted n-type doping [1]. However, the absence of dopant electrical activation after implantation and thermal annealing is a technological obstacle to be removed to achieve localized n-type and p-type doping.

In this work, we focus our attention on boron over-doped implanted diamond layer. We performed implantation on (100)-oriented diamond single crystals by high temperature beam line ion implantation and by beam line followed by a co-implantation plasma immersion ion implantation (PIII). The boron depth profiles in the implanted diamonds are measured by secondary ion mass spectrometry (SIMS). They confirm an almost constant concentration of implanted species at a 200 nm depth (box-profiles): 1.6×10^{20} B/cm3 for high temperature implantation. Plasma immersion ion implantation (PIII) add a boron concentration peak of $2-3 \times 10^{20}$ B/cm3 at diamond extreme surface. Transmission Electron Microscopy (TEM) images performed on as implanted samples indicate damages on diamond crystal induced by implantation, but no amorphization. After high thermal annealing at 1700°C during 30 min, SIMS analysis evidences the loss of the boron surface peak obtained by PIII while diamond recrystallization is observed by TEM together with an increase of the diamond surface roughness.

The comparison between the four-probes measurements on as implanted samples and after annealing shows a decrease of the measured sheet-resistance. This demonstrates a benefit of thermal annealing on the electrical activation of implanted boron. Hall measurements will complete these first results to evaluate the efficiency of both boron implantation and annealing conditions.

[1] Barjon et al. Physical Review B 89 (2014) 045201